

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Takashi SHIMADA, et al.

PCT Appln. No.: PCT/JP00/05797

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For: STRUCTURE INSPECTION APPARATUS

PRELIMINARY AMENDMENT

Commissioner for Patents
Washington, D.C. 20231

Sir:

Prior to examination, please amend the above-identified application as follows:

IN THE SPECIFICATION:**Page 20, Please amend the Second Full Paragraph to read as follows:**

a/ Fig. 13 illustrated the result of investigating a relation between the magnitude of vibration and the distance from a surface to a peeled off portion (part where aggregate, etc., is peeled off from the surrounding cement) as one example of an abnormal part, according to a similar procedure, wherein it is turned out that there is a strong correlation therebetween. Then, if the thresholds corresponding to the depths of peeled off portions are set to reference voltages V_1 , V_2 and V_3 of comparators 52₁, 52₂ and 52₃, respectively, of Fig. 16, it is possible to find the distances to the internal defects by the number of lit LEDs 53, that is, in four stages in this case.

Page 25, Please amend the First Full Paragraph to read as follows:

As shown in Fig. 16, a display device 13A of this fifth embodiment is provided with a plurality of comparators 52₁ - 52₃ arranged in parallel with each other, so that setting reference

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